Annealing-induced changes of the magnetic anisotropy of (Ga,Mn)As epilayers

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The dependence of the magnetic anisotropy of As-capped (G a,M n)As epilayers on the annealing parameters – temperature and time – has been investigated. A uniaxial magnetic anisotropy is evidenced, whose orientation with respect to the crystallographic axes changes upon annealing from [110] for the as-grown samples to [110] for the annealed samples. Both cubic an uniaxial anisotropies are tightly linked to the concentration of charge carriers, the magnitude of which is controlled by the annealing process.

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Considerable experim ental and theoreticale orts have recently been devoted to the study of III-V diluted magnetic sem iconductors (DMS) due to their potential implem entation as spintronic devices [1]. The high ferrom agnetic transition temperature of (Ga,Mn)Ashasmade this com pound one of the most investigated III-V DMS, being regarded as the prototype of this new class of materials [2]. It is well established now adays that the ferrom agnetic interaction between the magnetic ions is mediated by the charge carriers, holes in this case, and that point defects such as As antisites (As $_{Ga}$ ) and Mn interstitials (Mn $_{I}$ ) play a crucial role in determ in ing the magnetic properties of (Ga,Mn)As [3, 4, 5]. Optimal annealing experiments have proved that the highly m obile M  $n_{\scriptscriptstyle \rm I}$  defects [3] outdi use to and are passivated at the free surface [5, 6] and that in all successful annealings the M  $n_{\rm I}$  concentration is higher than the concentration of A  $s_{Ga}$ . The removal of M  $n_T$  from the bulk of (G a, M n) As leads to an increase of the ferrom agnetic transition temperature ( $T_{C}$ ), carrier concentration and average m anganese m agnetic m oment. However, one particular aspect of the magnetic properties is not fully understood and this concerns the m agnetic anisotropy. Experim entally it is found that a strong uniaxial (UA) contribution to the overallm agnetic anisotropy appears along the [110] direction [7, 8, 9]. Although the (Ga,Mn)As structure is tetragonally distorted due to its lattice m ism atch with the GaAs substrate, structural characterization comm only shows that the epilayers are coherently strained to the substrate [10] and this holds even for very large thicknesses of the order of a few m [8]. Theoretical investigations explain fairly well the in uence of the biaxial strain and hole concentration on the magnetic anisotropy [11, 12]. However, based on sym m etry argum ents the tetragonal distortion cannot account for the appearance of the uniaxial anisotropy. A nisotropy m easurem ents on as-grown samples of dierent thicknesses [8] and on annealed-and-etched samples [9] have shown that the UA contribution does not have a surface or interface origin. Instead, it has been suggested by Sawickiet al. [9] that the UA originates from a small

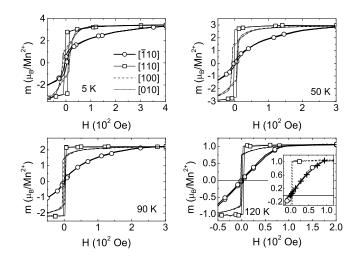


FIG. 1: Field dependence of the magnetization recorded at dierent temperatures for a 1000 A thick sample annealed at 240 C for 10h. The crosses in the inset of the 120K' pane represent a to the hard axis magnetization as discussed in the text.

trigonal distortion  $_{\rm xy}$   $\rm 60$ ; using the p  $\,$  d Zener m odel of the ferrom agnetism they estim ate that  $_{\rm xy}$  = 0.05% is enough to explain the experim entally observed U.A . The m icroscopic origin of the trigonal distortion could be surface A s-dim erization, resulting in surface reconstruction and an inequivalence between the [110] and [110] directions [7].

The G  $a_{1}$  x M  $n_x$ As (x 0.06) sam ples were grown on (001) G aAs substrates by low-tem perature molecular beam epitaxy at a growth tem perature ( $T_g$ ) of about 230 C. Further details on the sam ple preparation are given elsewhere [13]. For an elecient annealing, a rather thick capping layer of amorphous As was deposited on top of (G  $a_x$ M n)As. Pieces of the as-grown samples were annealed in air at dierent annealing temperatures ( $T_a$ ) and for dierent annealing times ( $T_a$ ). We have shown that the dependence of  $T_c$  on the annealing time has a peculiar variation due to the presence of the amorphous cap [6]. Depending on the position of  $T_a$  with respect to  $T_g$ ,  $T_c$ —peaks appear at certain values of  $T_a$  ( $T_a$ ). In this study we focus only on  $T_a$  either lower (215 C) or

TABLE I:  $T_{\text{C}}$  values for the 1000 A and 300 A thick samples annealed at 215 C and 240 C for dierent  $t_{\text{a}}$ . The as-grown samples are denoted by a'.

					t= 1000 A			
Ta	а	j		215 C		j	240 C	
t <sub>a</sub>		j	3h	7h	10h	j 1h	4h	10h
T <sub>C</sub> (K)	76	j	127	136	132	j 127	145	130
					t= 300A			
Ta	a	j		215 C	t= 300A	j	240 C	
T <sub>a</sub>	a	j	1h	215 C 5h	t= 300A 9h	j j 3h	240 C 4h	10h

higher (240 °C) than  $T_g$ . The annealing times are chosen relative to the  $t_a^{peak}$  position in order to cover  $t_a$ -regions below and above  $t_a^{peak}$  [6].

The magnetic anisotropy of the samples was assessed eld-dependent m easurem ents of the m agnetization recorded in a Quantum Design MPMS-XLSQUID magnetom eter. For a detailed investigation of the magnetic anisotropy, hysteresis loops were measured along four di erent crystallographic directions, nam ely [100], [110], [010] and [110], and at di erent tem peratures, both for the as-grown and annealed samples. An example of such hysteresis loops is shown in Fig. 1 for a 1000 A thick sam ple annealed for 10h at 240 C. The  $T_C$  was derived from the tem perature dependence of the magnetization, M (T), as the onset of the FM order;  $T_{\mathbb{C}}$  values for the di erent sam ples are sum marized in Table I. The free energy density, considering a cubic, an uniaxial and a Zeem an term, can be written as  $e = K_c \sin^2() \cos^2() +$  $_{\rm H}$  ), where and  $_{\rm H}$  $K_u \sin^2 ($ =4) $_{0}$ M  $_{s}$ M  $_{\odot}$ ( give the orientation of the saturation m agnetization ( $M_s$ ) and applied eld with respect to the [100] direction, arbitrarily chosen as a reference axis. In our m easurem ents, therefore assumes the following values 0, =4, =2and 3 =4. M in im ization of the free energy with respect to the angle, and for particular values of H, gives relations between the applied eld and the magnetization as in Eq.1 ( $_{\rm H}$  = 3 =4).

$$\frac{2K_{c}}{_{0}M_{s}}^{2} = \frac{M}{M_{s}}^{3} = \frac{M}{M_{s}}^{4} + \frac{2K_{u}}{_{0}M_{s}} \frac{M}{M_{s}} = H$$
 (1)

The anisotropy constants, K  $_{\rm u}$  and K  $_{\rm c}$ , are found from ts to the measured hard-axis magnetizations, with the hard-axis corresponding to the [110] and [110] directions for the as-grown and annealed samples, respectively. An example of such a tis shown in the inset of the 120 K' pane of Fig. 1 (the tis marked by crosses). One should stress that errors stemming from determination of the sample volume (thickness and area) directly in uence the value of the saturation magnetization and as a result rather large relative errors of 5 10% are introduced when calculating the anisotropy constants.

Figures 2 and 3 show the temperature dependence of the anisotropy constants for the 1000 A and 300 A thick

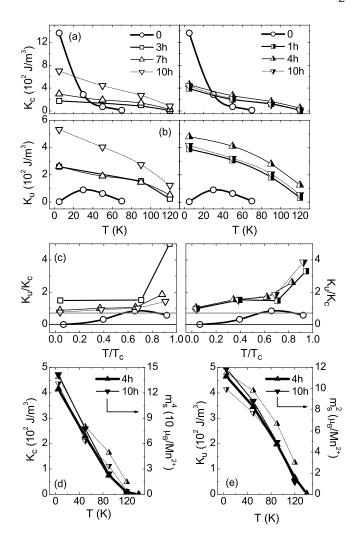


FIG. 2: (a) and (b) K  $_{\rm c}$  and K  $_{\rm u}$  vs. tem perature for a 1000 A – thick sam ple annealed at 215 C (empty symbols, left hand panes) and 240 C (half-led symbols, right hand panes). (c) The ratio K  $_{\rm u}$  =K  $_{\rm c}$  as a function of the reduce tem perature T=T $_{\rm c}$  for T $_{\rm a}$  = 215 C (left hand pane) and T $_{\rm a}$  = 240 C (right hand pane). (d) K  $_{\rm c}$  (dashed lines) and m  $_{\rm s}^4$  (solid lines) vs. tem perature (T $_{\rm a}$  = 240 C). (e) K  $_{\rm u}$  (dashed lines) and m  $_{\rm s}^2$  (solid lines) vs. tem perature (T $_{\rm a}$  = 240 C).

In s, respectively. The relative contribution of the two anisotropies to the overall anisotropy is given by the ratio K  $_{\rm u}$ =K  $_{\rm c}$ . This ratio is plotted in F igs. 2 (c) and 3 (c) for the two annealing tem peratures. If K  $_{\rm u}$ =K  $_{\rm c}$  > 1, the EA is pinned along [110]; if 0 6 K  $_{\rm u}$ =K  $_{\rm c}$  < 1, the EA assumes intermediate directions between [110] and [100]; if 1=  $\frac{1}{2}$  6 K  $_{\rm u}$ =K  $_{\rm c}$  < 1, the EA is closer to [110] and vice versa (the grey line in the gures corresponds to K  $_{\rm u}$ =K  $_{\rm c}$  = 1=  $\frac{1}{2}$ ). In the limit case of a cubic anisotropy, i.e. EA along [100], K  $_{\rm u}$  tends to zero. All these situations can be easily seen in the hysteresis loops. For instance, in Fig. 1, at 5 K , K  $_{\rm u}$ =K  $_{\rm c}$  = 0.9, thus the EA is very close to [110], while at elevated tem peratures, as K  $_{\rm u}$ =K  $_{\rm c}$  exceeds 1, square hysteresis loops are obtained with M  $_{\rm r}^{\rm [110]}$ , M  $_{\rm s}$ ,

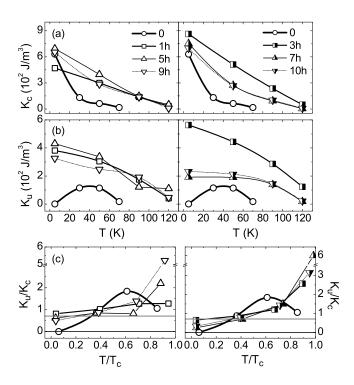


FIG. 3: (a) and (b) K  $_{\rm c}$  and K  $_{\rm u}$  vs. tem perature for a 300-A – thick sample annealed at 215 C (empty symbols, left hand panes) and 240 C (half-led symbols, right hand panes). (c) The ratio K  $_{\rm u}$  =K  $_{\rm c}$  as a function of the reduced temperature T=T $_{\rm c}$  for T $_{\rm a}$  = 215 C (left hand pane) and T $_{\rm a}$  = 240 C (right hand pane).

where M  $_{\rm r}$  is the rem anence m agnetization. In Fig. 2 (d) and (e), one m ay notice that K  $_{\rm c}$  and K  $_{\rm u}$  exhibit a tem – perature dependence in agreement with that of m  $_{\rm s}^4$  and m  $_{\rm s}^2$ , respectively, as expected for the cubic and uniaxial anisotropy term s.

For the as-grown samples we not that at low temperatures the uniaxial contribution is negligible as compared to cubic one; the ratio K  $_{\rm u}$ =K  $_{\rm c}$  approaches zero in this case, and thus an equivalence between the hl00i and hl10i axes is found in the hysteresis loops. As the temperature increases, K  $_{\rm c}$  has a rapid fall-o and an uniaxial contribution appears with the EA oriented (roughly) along [110]. It should be noted, using the free energy expression for the magnetization given above, that the extracted value of K  $_{\rm u}$  is negative for the as-grown samples. However, in Figs. 2 (b) and 3 (b) the magnitude of K  $_{\rm u}$  is plotted instead. Furthermore, the temperature dependence of K  $_{\rm u}$  is similar for both the 1000 A and 300 A thick samples, whereas K  $_{\rm c}$  is larger for the 1000 A sample than for the 300 A sample.

A 90-degree rotation of the UA takes place upon annealing. This rotation occurs even for very short  $t_a$  signaling a strong correlation between the UA direction and the hole concentration as pointed out recently by Sawicki et al. [9]. For  $T_a$  close to  $T_g$  short annealing times are needed to readily deplete the bulk of (G a,M n)As from M n\_I, and thus a large increase of the hole concentration is expected [6]. A nother manifestation of the close connection between magnetic anisotropy and carrier concentration is the variation of the anisotropy constants with  $t_a$  since both K  $_c$  and K  $_u$  exhibit maxima at  $t_a=t_a^{\rm peak}$ ; a maximum in hole concentration at  $t_a=t_a^{\rm peak}$  was inferred from the annealing experiments reported in Ref. [6].

In sum mary, we have shown that both cubic and uniaxial anisotropies appearing in (G a,M n)A s are in uenced by changes in the hole concentration, which in turn is controlled by the di erent annealing parameters.

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